

Supporting Information

Oxygen-Vacancy Rich in Melilite to Modulate the Persistent Luminescence for Multi-Functional Application

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Experimental section:

Sample preparation

All phosphors were synthesized using a traditional solid-state method. The raw materials were CaCO_3 (99.99%), MgO (99.99%), SiO_2 (A.R.), and Eu_2O_3 (99.99%), which were used directly without any further treatment. The stoichiometric starting materials were thoroughly homogenized, the mixture was transferred into an alumina crucible and then loaded into a muffle furnace. Then the mixed samples were sintered at 1150 °C for 5 h under 95% N_2 +5% H_2 reductive atmosphere. The obtained samples were cooled to room temperature and then ground again in an agate mortar. Finally, the solid powder samples were sintered at 550 °C in H_2 for 1h, 3h and 5 h to obtain the V_O -CMSE for subsequent analysis and measurements.

Characterization

The powder X-ray diffraction (PXRD) patterns of the as-obtained samples were collected on a X' Pert PRO diffractometer (Cu $\text{K}\alpha$ radiation, $\lambda = 1.5406 \text{ \AA}$) at 298 K. The microstructure was analyzed using a scanning electron microscope (SEM, JSM-6700F) and transmission electron microscope (FE-TEM, JEM-2100F, JEOL). The X-ray photoelectron spectroscopy (XPS, Thermo fisher Scientific K-Alpha) was conducted to identify the chemical states of the elements in the sample. A FLS-980 fluorescence spectrophotometer (Xe 900, 450 W arc lamps) was employed to obtain the photoluminescence (PL), photoluminescence excitation (PLE), and decay curve spectra. An absolute photoluminescence quantum yield measurement system (Hamamatsu, Quantaaurus-QY plus C13534-31) was adopted to test the quantum

efficiency. A LTTL-3DS measurement was used to record the 3D TL glow curves at a heating rate of $2 \text{ K}\cdot\text{s}^{-1}$.

Computational methods:

Utilizing density functional theory (DFT) as implemented in the Vienna *ab-initio* simulation package code,¹ we investigate the electronic structures of title compound. We used projector augmented wave (PAW) method² for the ionic cores and the generalized gradient approximation (GGA) for the exchange-correlation potential, in which the Perdew-Burke-Ernzerhof (PBE) type³ exchange-correlation was adopted. The reciprocal space was sampled with 0.03 \AA^{-1} spacing in the Monkhorst-Pack scheme for structure optimization, while denser k-point grids with 0.01 \AA^{-1} spacing were adopted for properties calculation. We used a mesh cutoff energy of 400 eV to determine the self-consistent charge density. All geometries are relaxed until the Hellmann-Feynman force on atoms is less than 0.01 eV/\AA and the total energy change is less than $1.0 \times 10^{-5} \text{ eV}$. The calculation models were built from the crystal structure. To calculate the formation energy of oxygen vacancies, the following equation was used: $E_{\text{vac}} = E(\text{slab+Ovac}) - E(\text{slab}) - E(\text{O})$. Here, $E(\text{slab+Ovac})$, $E(\text{slab})$, and $E(\text{O})$ denote the energies of the surface with one oxygen vacancy, the clean surface, and the isolated oxygen atom, respectively.

[1] A. G. Kresse, J. Furthmüller, Efficient iterative schemes for ab initio total-energy calculations using a plane-wave basis set. Phys. Rev. B 1996, 54, 11169.

[2] B. G. Kresse, J. Furthmüller, Efficiency of Ab-initio total energy calculations for metals and semiconductors using a plane-wave basis set. *Com. Mater. Sci.* 1996, 6, 15-50.

[3] J. P. Perdew, K. Burke, M. Ernzerhof, Generalized gradient approximation made simple. *Phys. Rev. Lett.* 1996, 77, 3865.

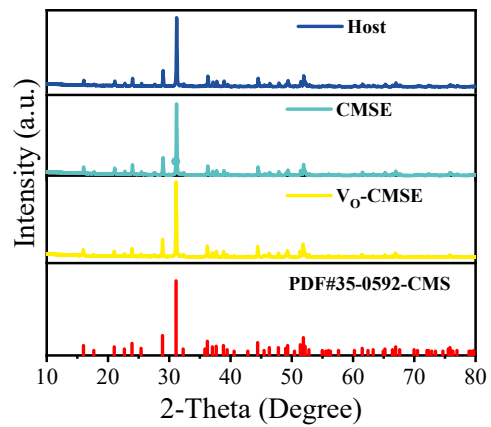


Fig. S1 Powder XRD patterns of CMSE and V_O-CMSE.

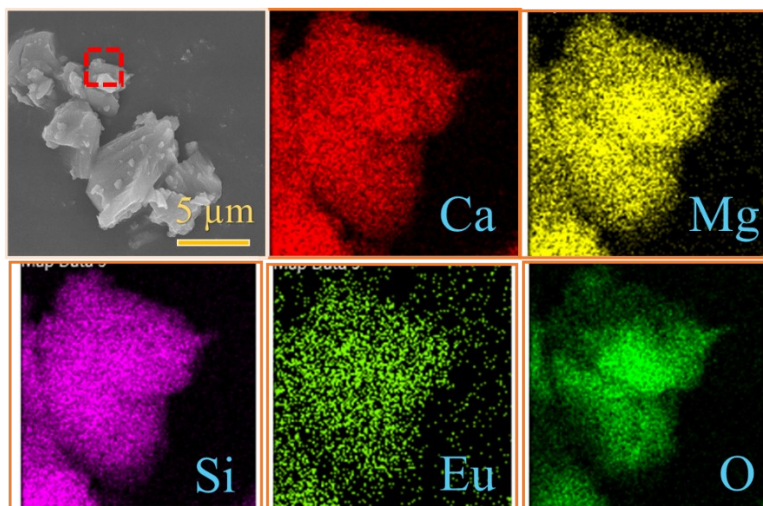


Fig. S2 SEM and EDS element mapping images of V_O-CMSE.

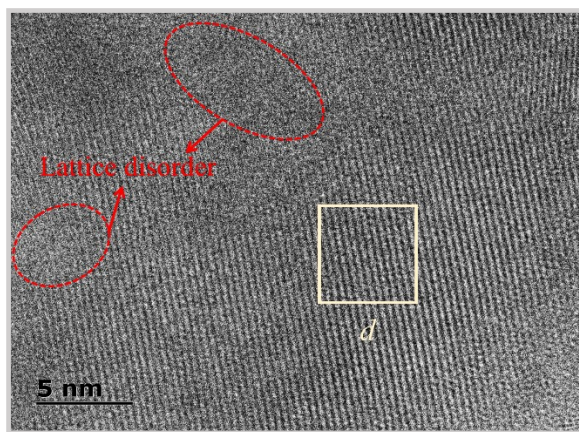


Fig. S3 High-resolution TEM image of V_O-CMSE, the lattice disorder induced by defects is marked by red arrows.

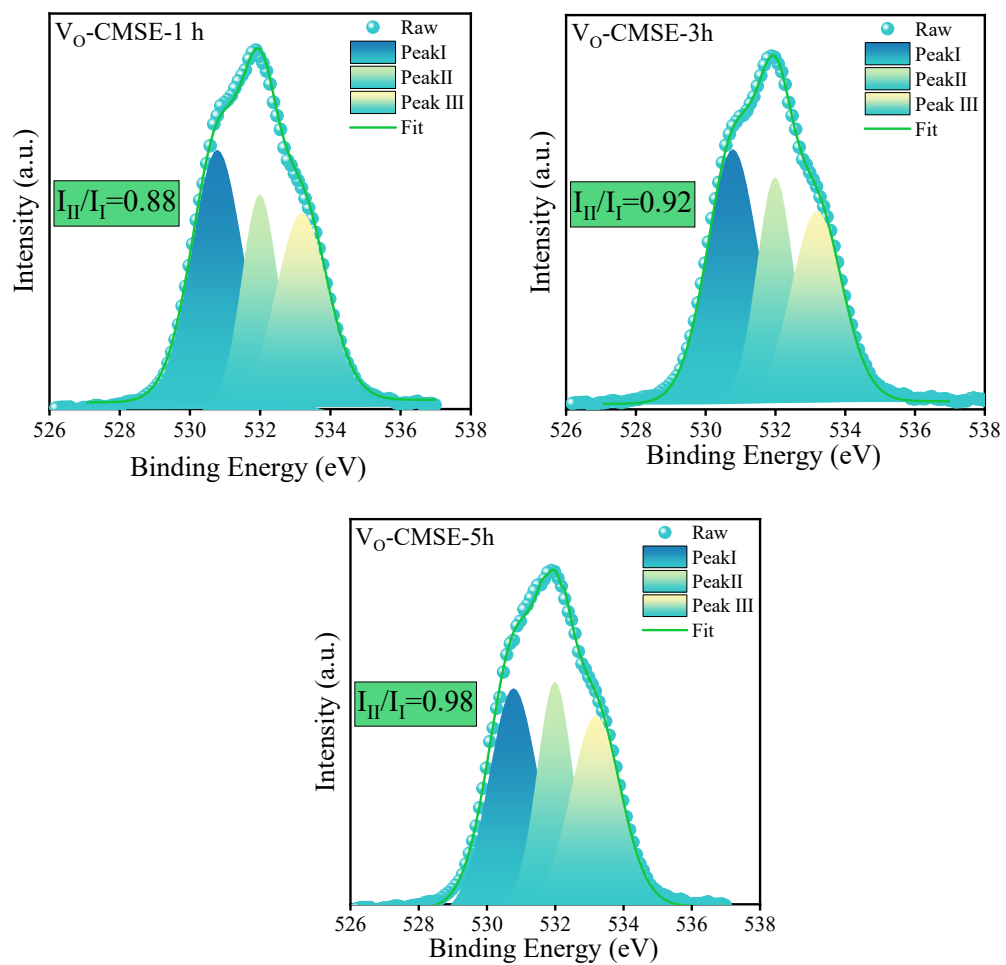


Fig. S4. Fitted O 1s XPS spectra of CMSE under various treatment time.

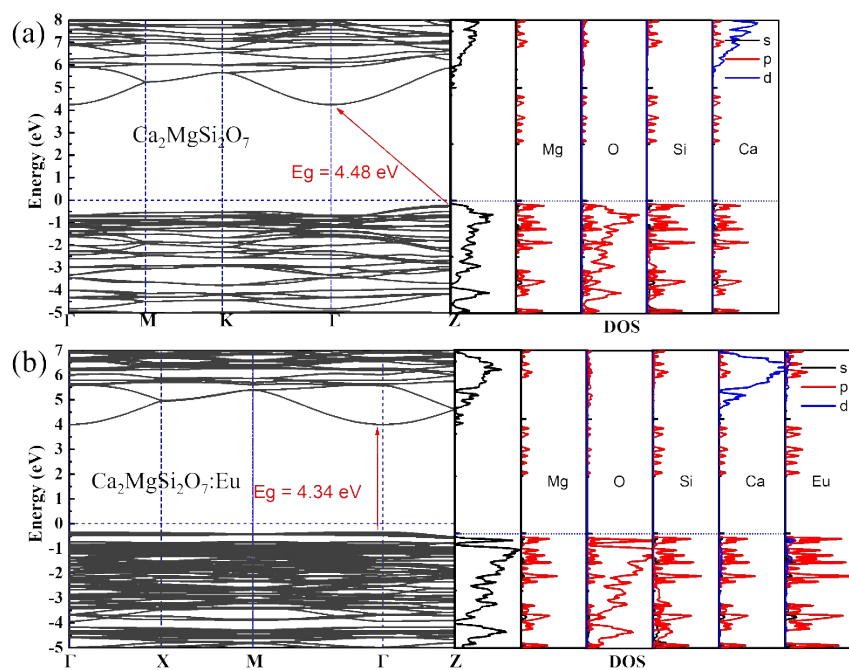


Fig. S5 Bandgaps and DOSs of CMS and CMSE.

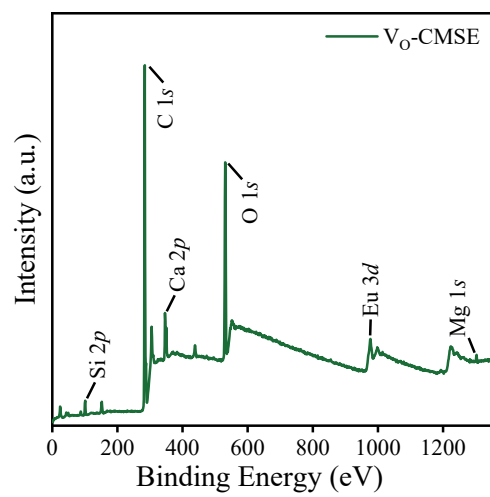


Fig. S6 XPS spectrum of V_O-CMSE.

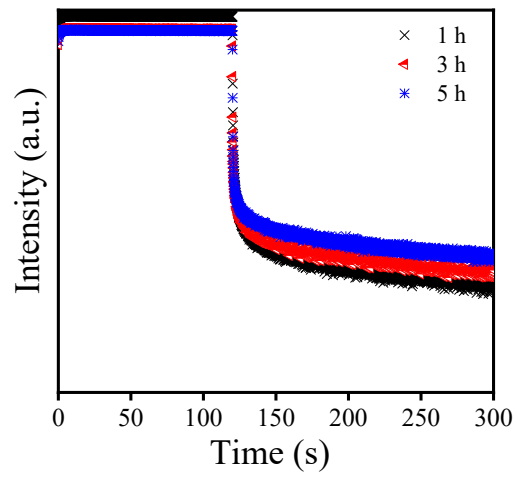


Fig. S7 PersL decay curves of V_O-CMSE under various treatment time.

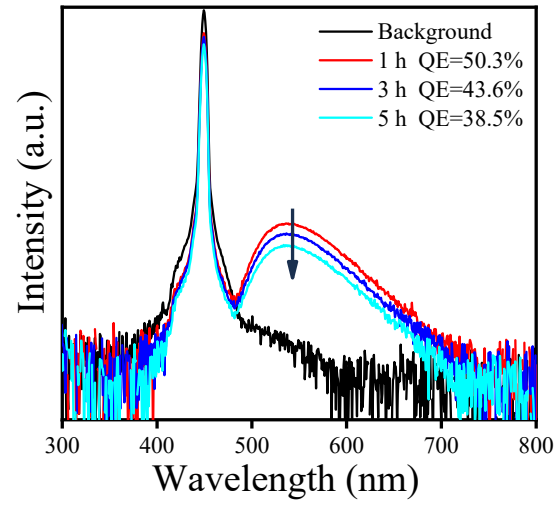


Fig. S8 The IQE value of VO-CMSE under 450 nm excitation.

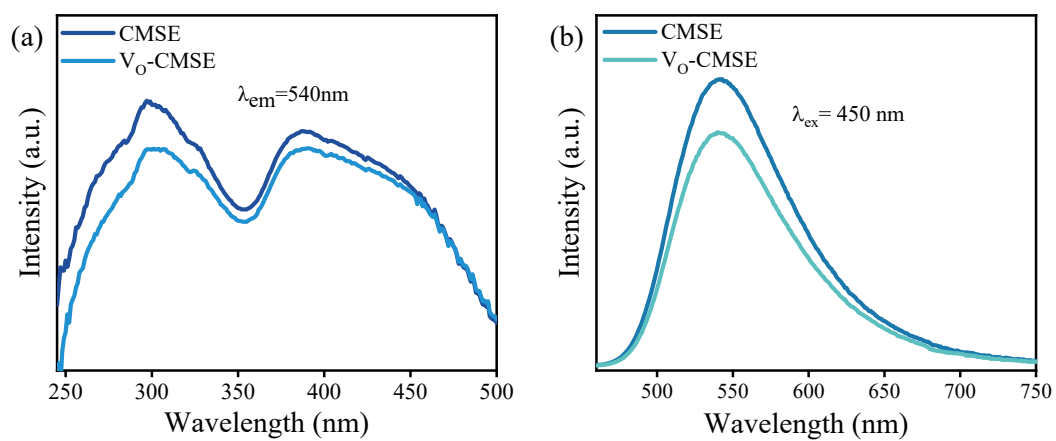


Fig. S9 PLE and PL spectra of CMSE and V_O-CMSE.

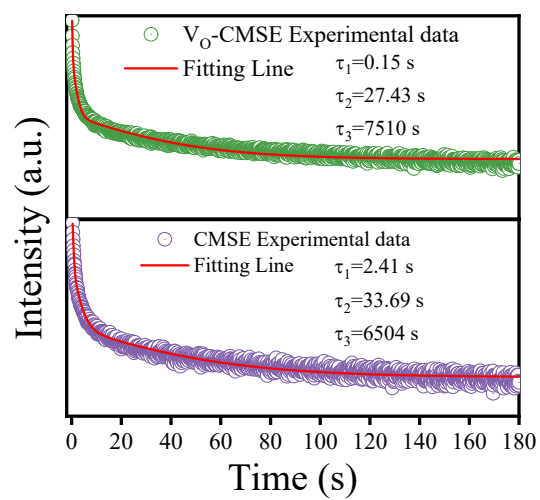


Fig. S10 PersL decay curves of CMSE and V_O-CMSE.

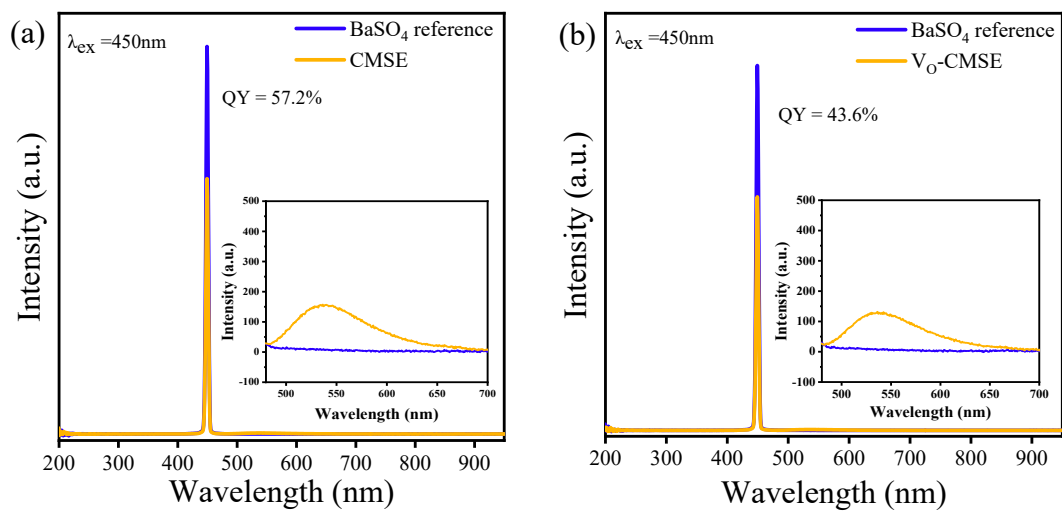


Fig. S11 QE values of CMSE and V_O-CMSE.

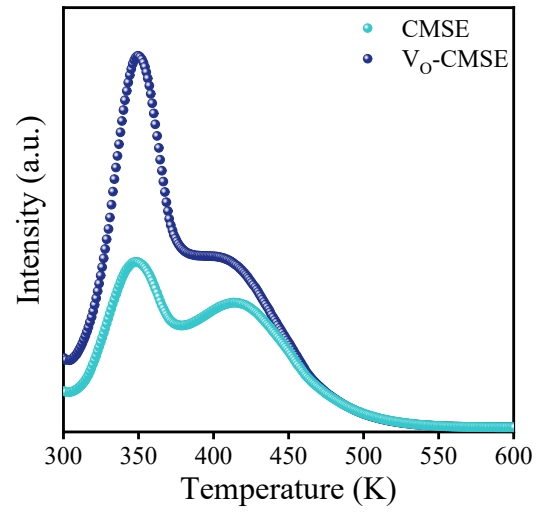


Fig. S12 TL spectra of CMSE and V_O-CMSE.

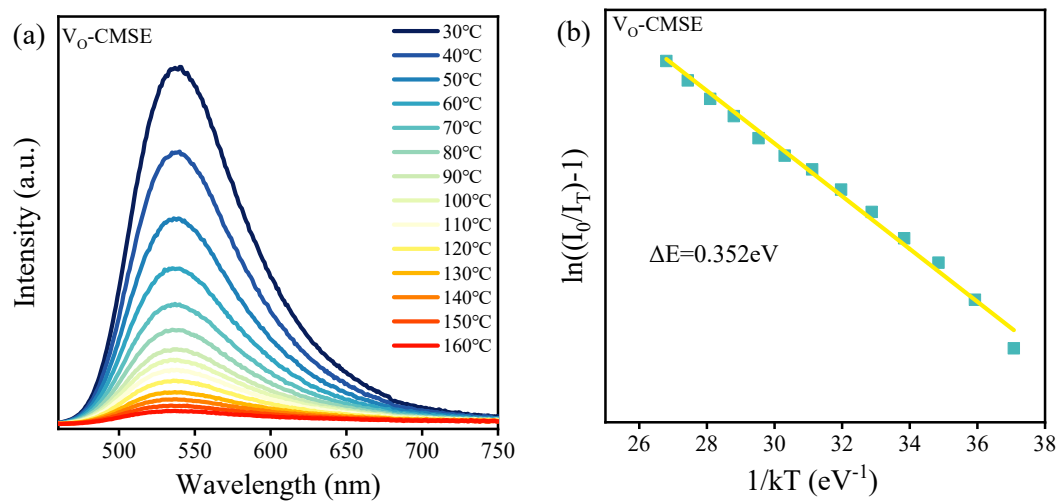


Fig. S13 (a) Temperature dependent PL of V_O-CMSE. (b) The calculated Ea value.